

Burn-in & Test Socket Workshop 2000

# Session 4a

# **Burn-in Board Design**











BURN-IN & TEST SOCKET WORKSHOP

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## **Presentations**

#### "Burn-in Board Design For Manufacturing"

Aamir Jamil Pycon, Inc.

"Burn-in Board Design Consideration For High Speed & High Power Devices"

Aamir Jamil Pycon, Inc.

#### "Burn-in Board Design Considerations"

Tony Valente Unisys – Unigen



# Burn-In Board Design For Manufacturing

#### **2000 Burn-in and Test Sockets Workshop**



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**Aamir Jamil** 

### Agenda

- Transition in Design
- Constraints
- SMT (Surface Mount Technology) contact: Case study
- Step board: Case Study

#### **Transition in Design**

• BIB(Burn-in Board) Devices require



#### **Transition in Design Cont'**

- BIB(Burn-in Board) Devices require
  - Sockets with Higher pin count
  - BIB design with higher density





### **Transition in Design Cont'**

- BIB(Burn-in Board) Devices require
  - More Layers
  - Matched impedance
  - Shorter cycle time
  - Higher efficiencies = better reliability



#### **Transition in Design Cont'**

- BIB(Burn-in Board) Devices require
  - SMT(Surface Mount Technology)
  - BGA (Ball Grid array)





#### Constraints

#### BURN-IN BOARD

MECHANICAL SPEC. OF THE CIRCUIT BOARD STANDARD 10 LAYER CONSTRUCTION FOR RELIABILITY STYLE OVEN

- Board size & thickness
  - Dedicated to 62
    mils(10Layer MAX
    with 50 
     < Imped.)</li>



- 1. All Cores are of **1oz Cu**
- 2. Trace Width = 8 Mils
- 3. Over all board thicknes 62 MILS +/- 10%
- 4. Impedance is 50 OHMS
- 5. Material is **POLYIMIDE**
- 6. Traces must be running **Perpendicular to the adjacent layers** in the Dual Stripline only.

- SMT Sockets
  - Device contact reliability
  - Socket contact reliability
  - Top probe for testing







- Thru-hole sockets
  - Higher drill count
  - Increases layer count
  - Higher aspect ratio required







- SMT Components
  - Vias too close to Pads, causes solder bridge and Solder Escape



- SMT Components
  - Assembly to use Re-Flow for SMT and Wave solder for Through Hole components.



- Power planes
  - Require higher CU count
  - Additional Power planes
- Signal Layer
  - Require higher number of signal layers
  - Require smaller trace width and line spacing

## SMT contact: Case study

- Problem
  - Devices fail randomly in SMT sockets.
- Diagnosis
  - Contact issues b/w BIB Pads and socket pins
  - Contact issues b/w socket pins and DUT contacts
  - Oxidation on BIB SMT pads







## SMT contact: Case study

- Solution
  - High pressure wash and bake BIB
  - BIB Pad cleaning using Alcohol before installing sockets



#### **Step Board: Case Study**

- Problem
  - Need 70+ Mils of layers on a 62 Mil BIB
- Non-Solutions
  - Squeezing design creates crosstalk issue
  - Squeezing layers creates impedance issue
- Step-board Solution
  - 70+ Mils in socket area, 62 Mils connector area
  - Add signal layers only under the socket area







## Burn-In Board Design consideration for High Speed & High Power Devices

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### Agenda

- Introduction to Design
- Memory Board Design
- Logic Board Design
- Simulation
- Fabrication & Assembly

#### Introduction to Design

- Static/Dynamic
  - Static: Constant power to device
  - Dynamic: Signals toggling
- TDBI (Test During Burn-In)
  - Monitor sign of life from device
  - Compare actual vs. expected
- Memory/Logic
  - Memory: Read & Write on the same channel
  - Logic: Dedicated output

#### **Memory Board Design**

- Device
  - Address inputs
  - I/O Bi-Directional
  - Small Foot Print High Density
- Design
  - 150+ devices per bib
  - Load per channel is higher
  - Isolation recommended
  - Rise time controlled by routing techniques





#### Memory cont'

- Routing & Termination
  - Parallel routing yields equal delay
  - AC termination yields low signal loss
  - Yields 10Mhz frequencies
  - Isolation protects from interference



AC Term.





**Parallel Routing** 



### Logic Board Design

- Device
  - BIST (Built-In Self Test)
  - Unidirectional channels
  - CLK parameters critical
  - PLL: Noise, Tr, Tf, Jitter
- Design
  - Large device Low density
  - Density = Channels dedicated for output
  - Skew: Clocks synchronized with inputs for expected output





#### Logic Board Design Cont'

#### Routing & Termination

- Pre design simulation for routing technique
- CLK routing point to point for Tr
- Serpentine routing for limited channels
- DC termination for better Tr
- AC termination avoids signal attenuation
- Impedance matched for device load



#### Simulation



#### Pre-Fabrication Simulation

- V/T graphs for all critical pins
- Adjust termination values
- Measure skew between signals
- Calculate Signal Integrity crosstalk
- 5% Accuracy between simulated and actual design





Refine Angle Field Walls Shade Print Quit



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- Pre-layout simulation
  - What-if scenario
  - Routing methodology for critical parameters
  - Termination selection
  - Component value estimation





AC Term.



#### FAT

- Fabrication
  - Number of layers, drill count/size and impedance requirement add to complexity
- Assembly
  - Pin count, pin length and mounting affect assembly
- Test
  - Design probe
  - Verify actual board with schematic

# Burn-In Board Design Considerations

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#### Agenda

- Mechanical Structures
  - Clam shell ("shadow spacing")
  - Mounting hardware
- Electrical impact
  - Pitch of pins
  - Routing layers
- Through Hole
  - Clam shell ("shadow spacing")
  - More stable mounting structure
- Surface Mount
  - Buried vias
    - Open routing paths
    - Testability

#### **Mechanical Structures**

- Clam Shell
  - Shadow spacing
- Open Top
  - Ability to move sockets closer than Clam Shell
  - Creates access to heat removal
- Mounting Hardware
  - Especially needed for SMT devices.
- Pin pitch
  - Reduces manufacturability

### Calculating Shadow Spacing



- $X = COS \ 85^{\circ} * 1.673$
- X = .087 \* 1.673
- X = .146
- Shadow Spacing = .394 + .146
- Shadow Spacing = .540
- Total distance between sockets would the length of the socket (1.555) plus the shadow spacing (.540). In this example the distance is 2.095 minimum between sockets.

10/11/9912/29/99

#### **Electrical Impact**

- Pin pitch
  - Tighter pitch decreases trace width (signal and power)
  - Spacing between rows of pins (in QFPs) decreases routing space
  - Hole diameter for pins (and pad size needed) decrease routing space
- Routing Layers
  - Decreased trace width may mean using multiple routing layers for Power and Ground.
  - With increased layer counts, overall board thickness will be effected.

## Through Hole vs. Surface Mount

#### • PROs

- More stable structure (pin vs vias)
- Access for all pins for testing.
- CONs
  - Pin lead length
  - Holes for all pins through board.

#### • PROs

- Blind vias would increase routing paths
- Easier to drill tolerance for vias vs pin diameter.
- Not limited by board thickness
- CONs
  - Blind vias limit accessibility for test.
  - More handling needed in assembly.